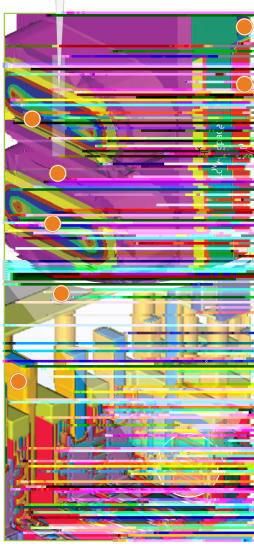




is a complete atomistic simulation toolkit developed and supported by world leading atomic-scale modeling experts. QuantumATK reduces time and cost in advanced semiconductor technology development by enabling earlier co-optimization of materials processes and transistors. The integration of QuantumATK with Sentaurus TCAD provides a seamless flow from material ϕ VW VX fTf f[bj a a g X c WgheX UX bj fl 4 ϕ Wf VT_X bW az ϕ b f a DhTagh 4G> eTaZX Yeb V_Iff VT_YbeVX X_W Ybe handling large and to some extent more realistic materials systems to ab initio tools that provide highly accurate results for smaller systems.



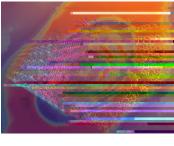




QuantumATK addresses key applications in the semiconductor industry and is a core component of the Synopsys Design-Technology Co-Optimization flow. QuantumATK offers modeling solutions for critical materials issues in advanced semiconductor technology development:

- Exploration of alternative interconnect metals
- Modeling and optimization of metal-semiconductor contacts
- Bandstructure and carrier transport modeling in new channel materials within quantized transistor structures
- · Exploration and optimization of high-k dielectric and ferroelectric stacks
- @XV[Ta\VT_` b\Wk_\aZ'bYVb_TcfX'bY af Ta\Vc_Tef
- And many other critical issues

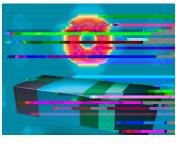
Highlighted Publications with QuantumATK



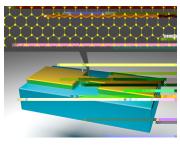
Study by IBM & GlobalFoundries | Lanzillo et al., Appl. Phys. Lett. 112, 163107 (2018)



Study by GlobalFoundries & IBM Research | Dixit et al., IEEE Trans. Elec. Dev. 64, 3775 (2017)



Study by Imec, PLASMANT and Synopsys QuantumATK Team | Sankaran et al., Phys. Rev. B 94, 094424 (2016)



Study by Fujitsu Ltd. and Fujitsu Laboratories Ltd. | Harada et al., Appl. Phys. Expr. 10, 074001 (2017)



Workfunction Engineering

Surface Scattering

Alternative Interconnect Metals

Contact Resistance

Dopant Diffusion/Activation in S/D



Study by IBM Research at Albany Nanotech and IBM T.J. Watson Research Center | Lanzillo et al., Comp. Mat. Sci. 158, 398 (2019)



- Support the screening and characterization of metal alternatives to Cu and barrier materials
- Calculate the mean free path and resistivity in metals and alloys and evaluate the impact of surface and grain boundary scattering
- Optimize the composition and thickness of diffusion barriers
- Calculate the resistance of the interface between interconnect and barrier metals

 Calculate bandstructures and extract band parameters to be inserted in TCAD advanced